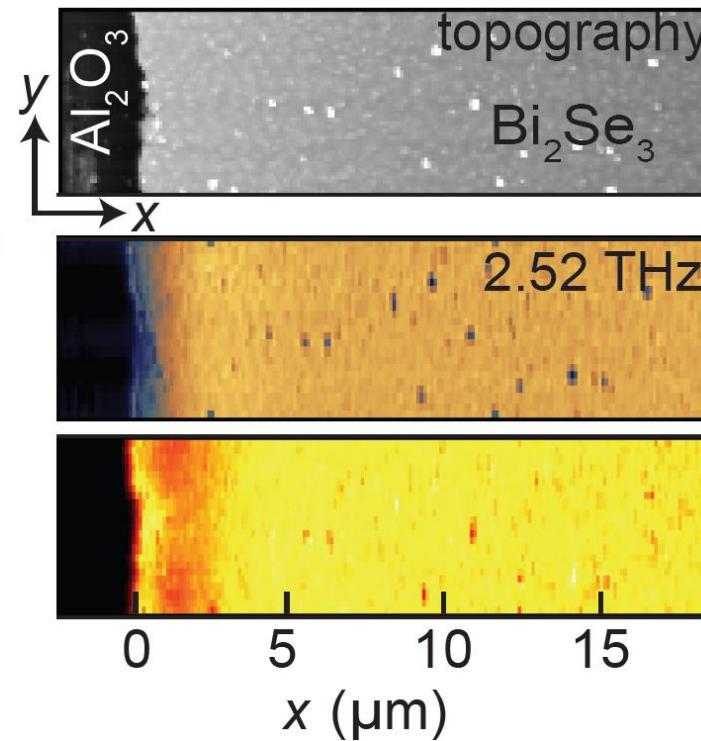
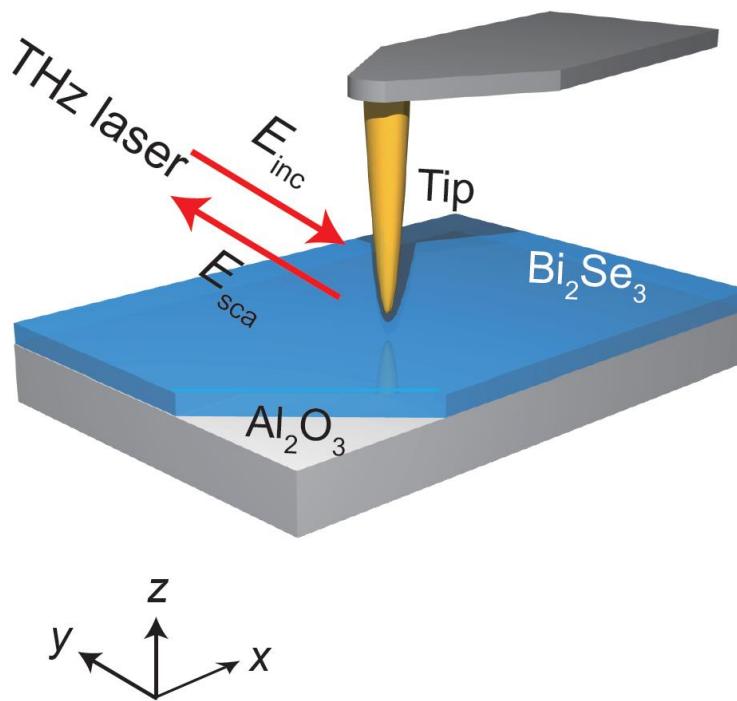


Real-space nanoimaging of THz polaritons in the topological insulator Bi_2Se_3

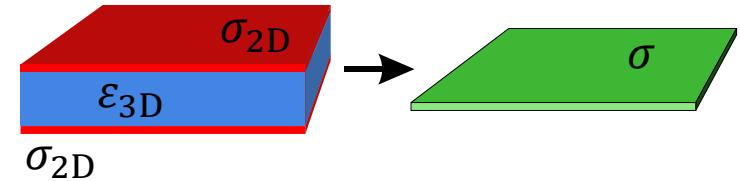
Andrei Bylinkin, Shu Chen, Zhengtianye Wang, Martin Schnell, Greeshma Chandan,
Peining Li, Alexey Y. Nikitin, Stephanie Law, Rainer Hillenbrand

Real-space nanoimaging of THz polaritons in the topological insulator Bi_2Se_3



Analytical polariton dispersion

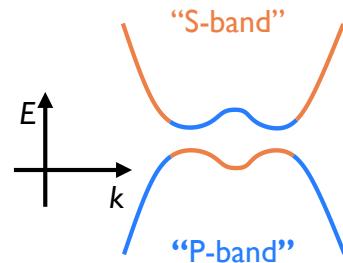
$$q_p(\omega) = i \frac{c}{4\pi} \frac{\epsilon_{\text{sub}} + 1}{\sigma(\omega)}$$



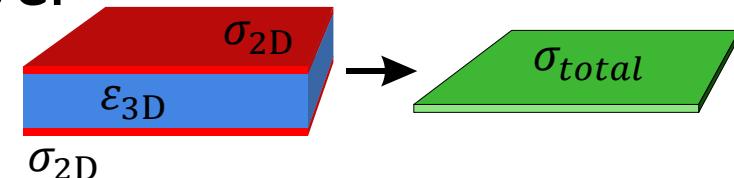
Shu Chen, Andrei Bylinkin, et al, in press

Plan

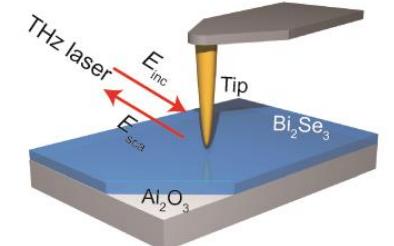
- Introduction and motivation



- Analytical polariton dispersion in complex multi-layer systems using the effective conductivity model

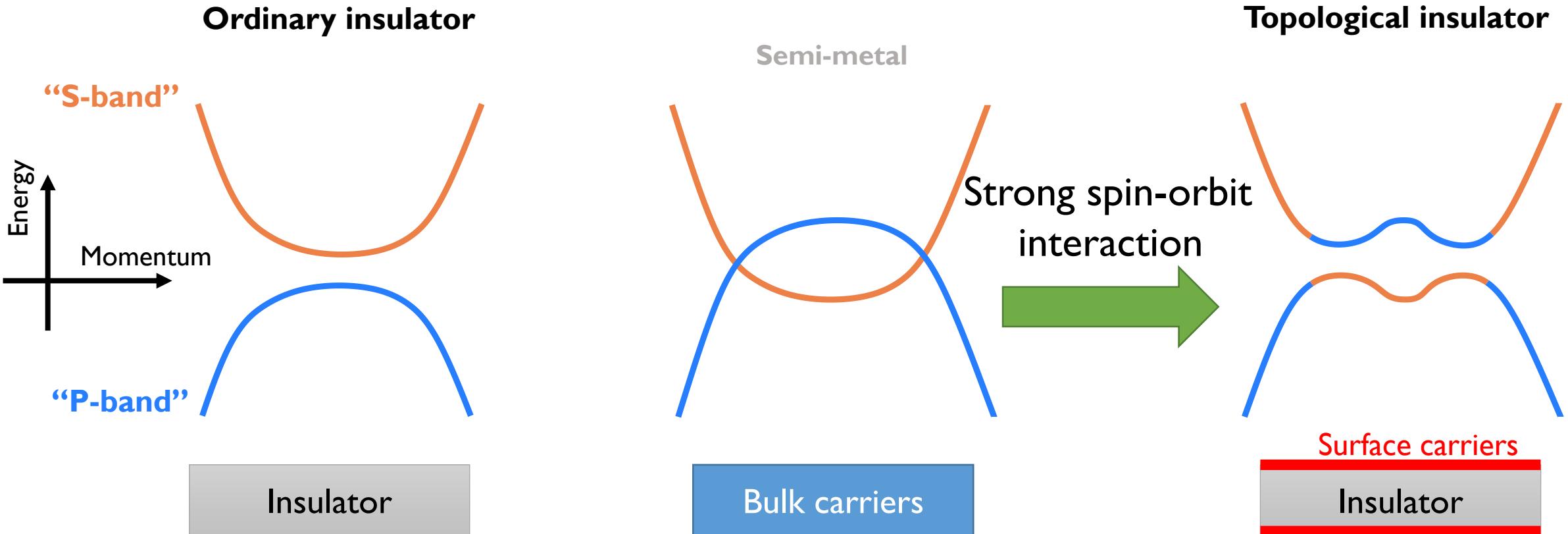


- THz real-space nanoimaging and complex analysis of polaritons in Bi_2Se_3



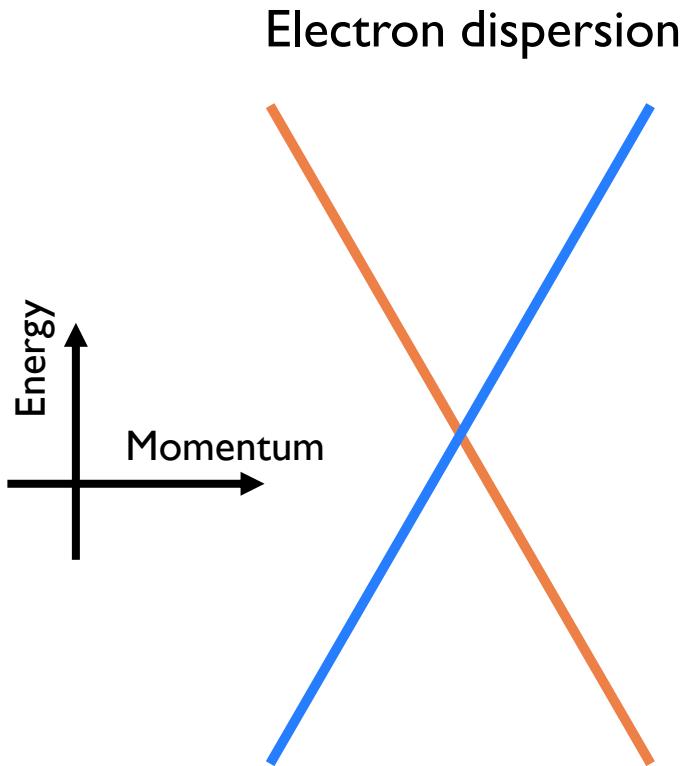
- Summary and outlook

| What is a topological insulator?



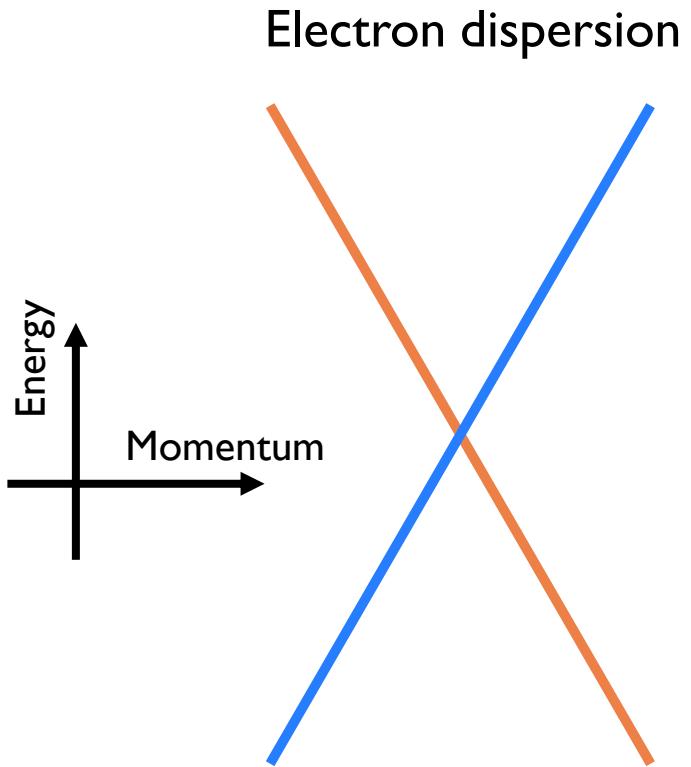
- Topological insulators exhibit conductive surface states with the linear dispersion

| What is interesting about topological insulators?



- Dirac carriers
- Spin-momentum locking

What is interesting about topological insulators?



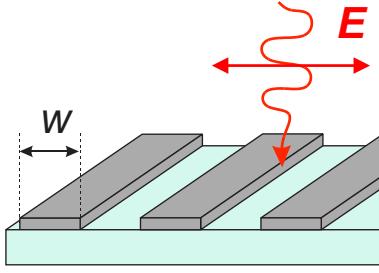
- Dirac carriers
- Spin-momentum locking

Plasmon polaritons

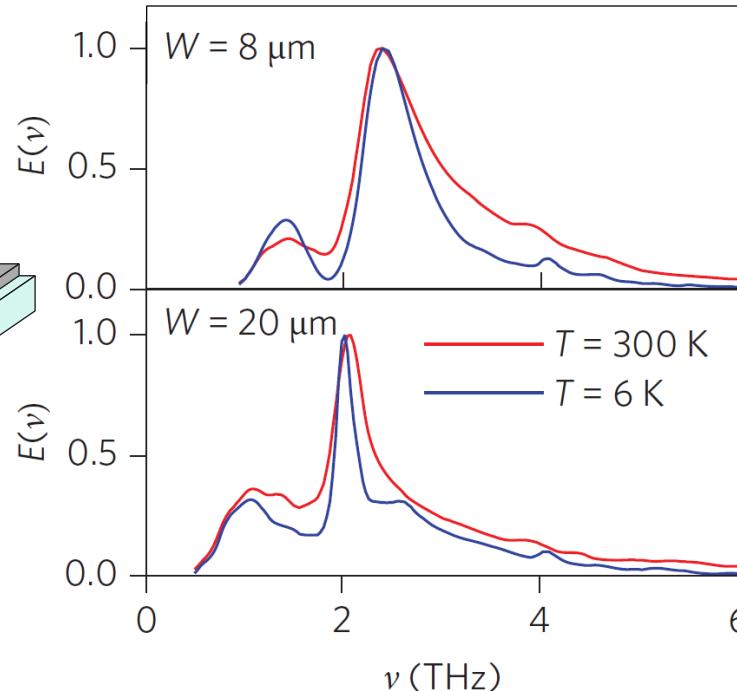
- $\omega_p \propto n^{1/4}$
- Spin-polarized plasmon waves

| THz far-field spectroscopy reveals polaritons in topological insulators (e.g. Bi_2Se_3)

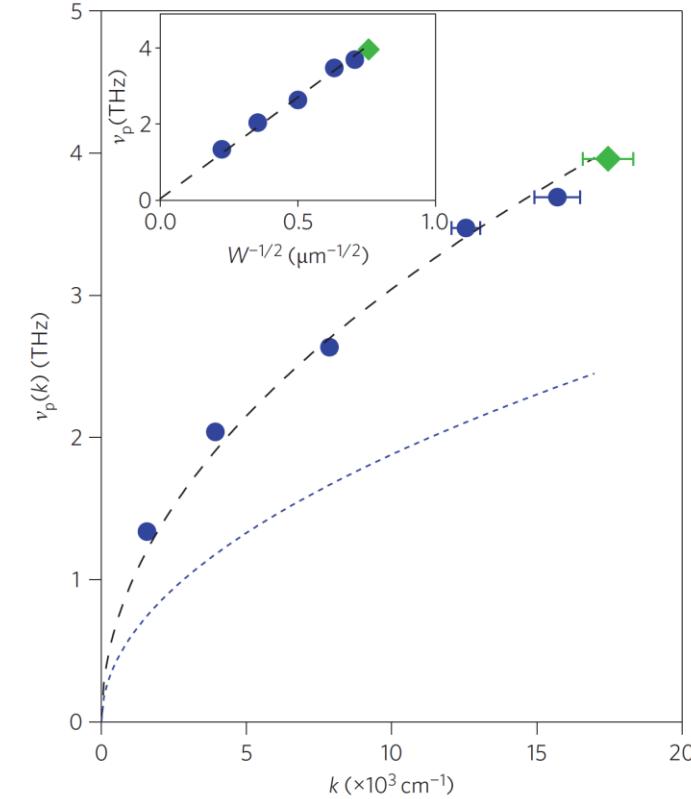
Bi_2Se_3 ribbons



Extinction coefficient



Plasmon dispersion



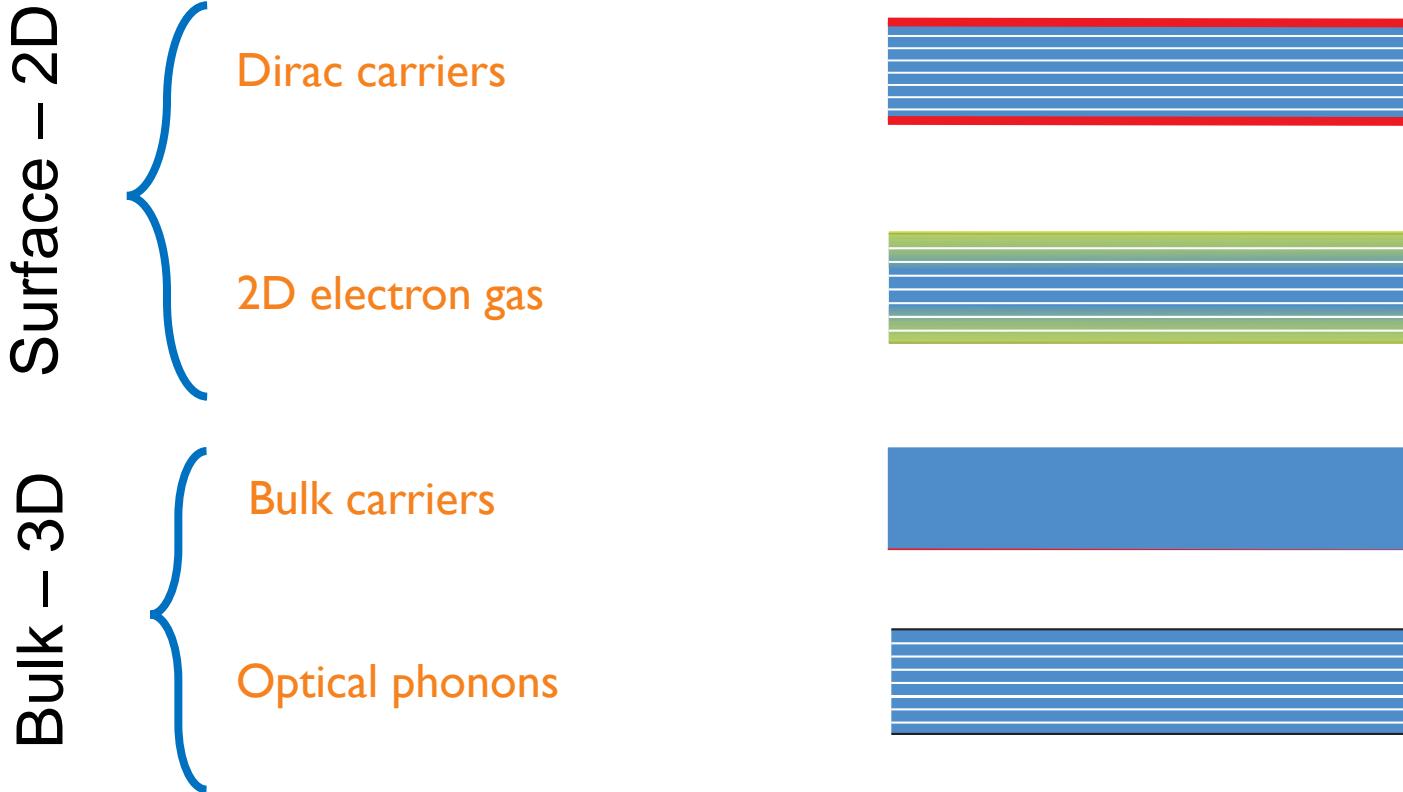
Dirac carriers

Bulk carriers

- Authors considered only **bulk** and **Dirac carriers**

Nature Nanotech. **8**, 556-560 (2013)

| Bi₂Se₃ is a complex material with surface (2D) and bulk (3D) states



$$\sigma_{\text{Dirac}} = \frac{e^2 v_F \sqrt{\pi n_{\text{Dirac}}}}{2 \hbar \pi} \frac{i}{\omega + i \gamma_{\text{Dirac}}}$$

$$\sigma_{\text{2DEG}} = \frac{e^2 n_{\text{2DEG}}}{m^*} \frac{i}{\omega + i \gamma_{\text{2DEG}}}$$

$$\varepsilon_{\text{Drude}} = - \frac{4 \pi n_{\text{bulk}} e^2}{m^*} \frac{1}{\omega^2 + i \omega \gamma_D}$$

$$\varepsilon_{\text{ph}} = \varepsilon_{\infty} + \sum_{i=1}^3 \frac{\omega_{p,i}^2}{\omega_{0,i}^2 - \omega^2 - i \omega \gamma_i}$$

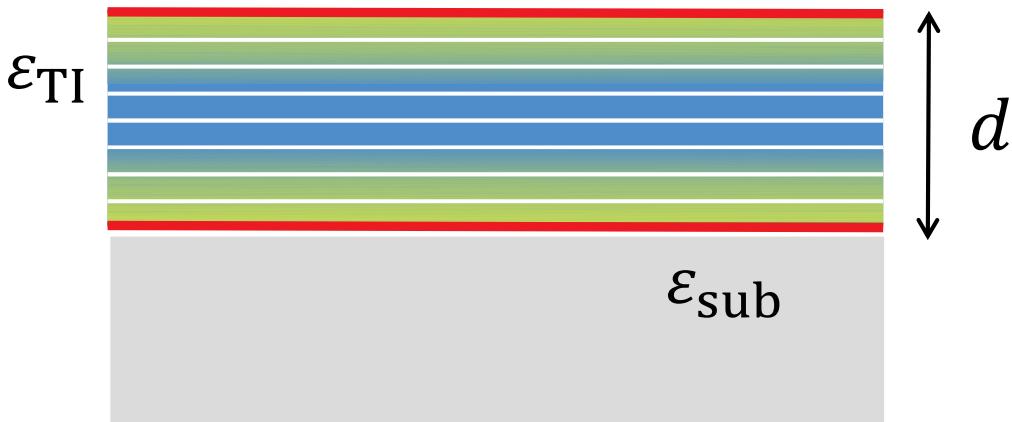
Advanced Optical Materials 6.13 (2018): 1800113.

Opt. Express 24, 7398-7410 (2016)

Phys. Rev. B 92, 205430 (2015)

Polariton dispersion in topological insulator from literature

Topological insulator



k_p – polariton wavevector

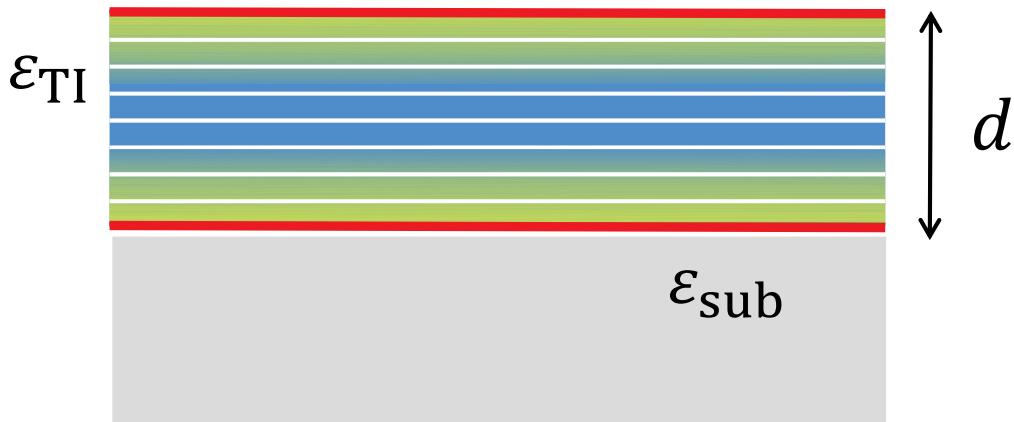
$$\omega_p^2 = \frac{2\alpha_d v_F E_F}{\hbar(\epsilon_{\text{sub}} + 1)} k_p \left[1 + \frac{k_p d \epsilon_{\text{TI}}}{\epsilon_{\text{sub}} + 1} \right]^{-1}$$

- It is difficult to separate surface (2D) and bulk (3D) contributions
- Equation is not valid when Fermi level of surface states are zero, $E_F = 0$

Phys. Rev. B 88, 205427 (2013)

Polariton dispersion in topological insulator from literature

Topological insulator



k_p – polariton wavevector

$$\omega_p^2 = \frac{2\alpha_d v_F E_F}{\hbar(\varepsilon_{\text{sub}} + 1)} k_p \left[1 + \frac{k_p d \varepsilon_{\text{TI}}}{\varepsilon_{\text{sub}} + 1} \right]^{-1}$$

Surface contribution (2D)

$$E_F = E_{F,\text{Dirac}} + 4E_{F,2\text{DEG}}$$

Bulk contribution (3D)

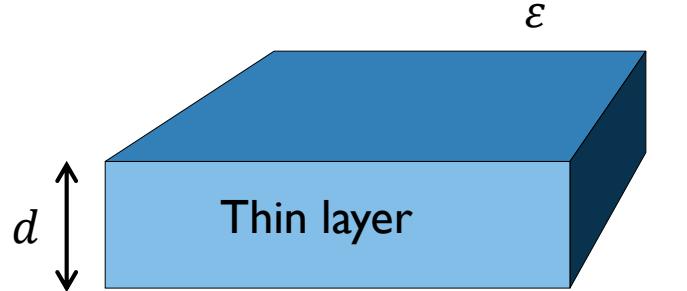
$$\varepsilon_{\text{TI}} = \varepsilon_{\text{Drude}} + \varepsilon_{\text{ph}}$$

- It is difficult to separate surface (2D) and bulk (3D) contributions
- Equation is not valid when Fermi level of surface states are zero, $E_F = 0$

Phys. Rev. B 88, 205427 (2013)

We used conductivity layer approximation to derive more intuitive equation

Step I



$$\sigma = \frac{\omega d}{4\pi i} \epsilon$$



- Thin layer material can be replaced by conductivity sheet assuming $k_p d \ll 1$

We generalized conductivity layer approximation for multi layer system

Step 2

Analytical polariton dispersion:

$$q(\omega) = \frac{k_p}{k_0} = i \frac{c}{4\pi} \frac{\varepsilon_{\text{sub}} + 1}{\sigma(\omega)}$$

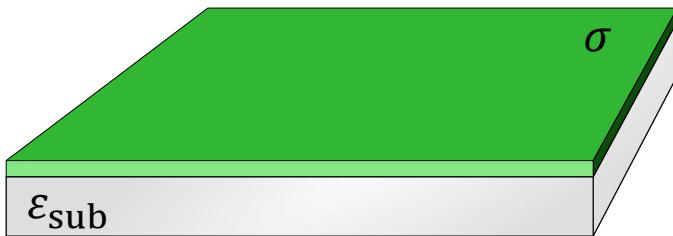


We generalized conductivity layer approximation for multi layer system

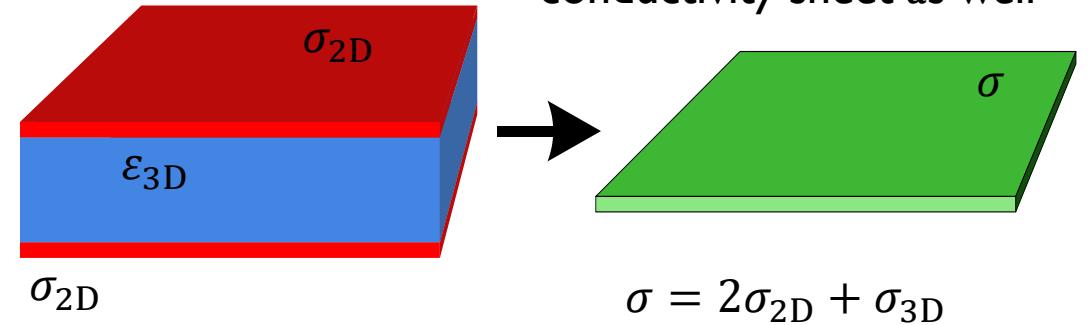
Step 2

Analytical polariton dispersion:

$$q(\omega) = \frac{k_p}{k_0} = i \frac{c}{4\pi} \frac{\varepsilon_{\text{sub}} + 1}{\sigma(\omega)}$$



Multi layer systems can be approximated by conductivity sheet as well

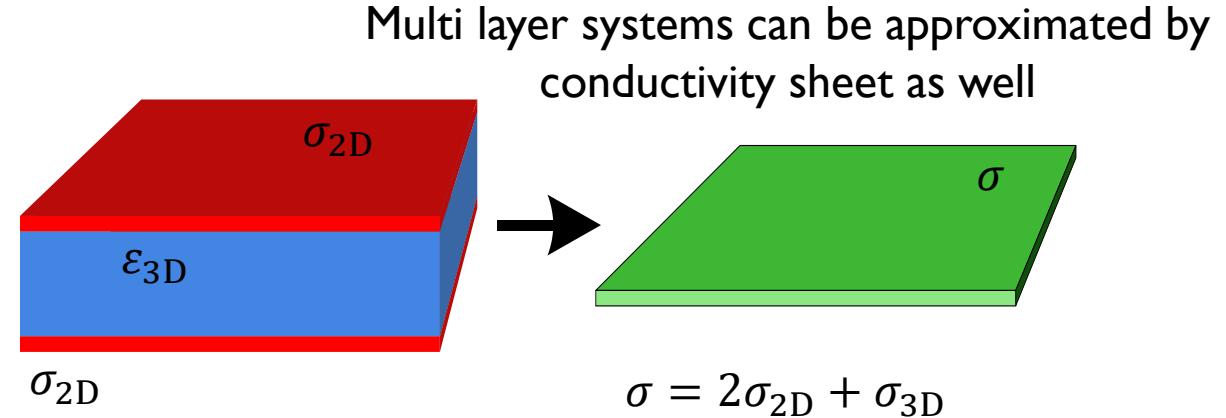
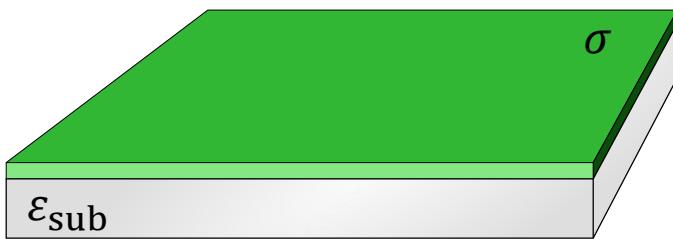


We generalized conductivity layer approximation for multi layer system

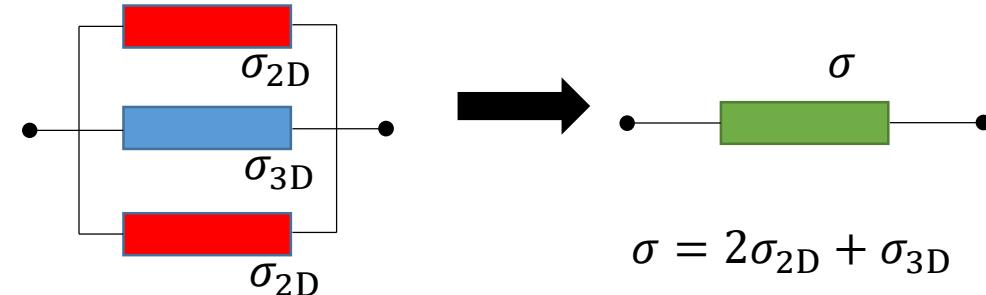
Step 2

Analytical polariton dispersion:

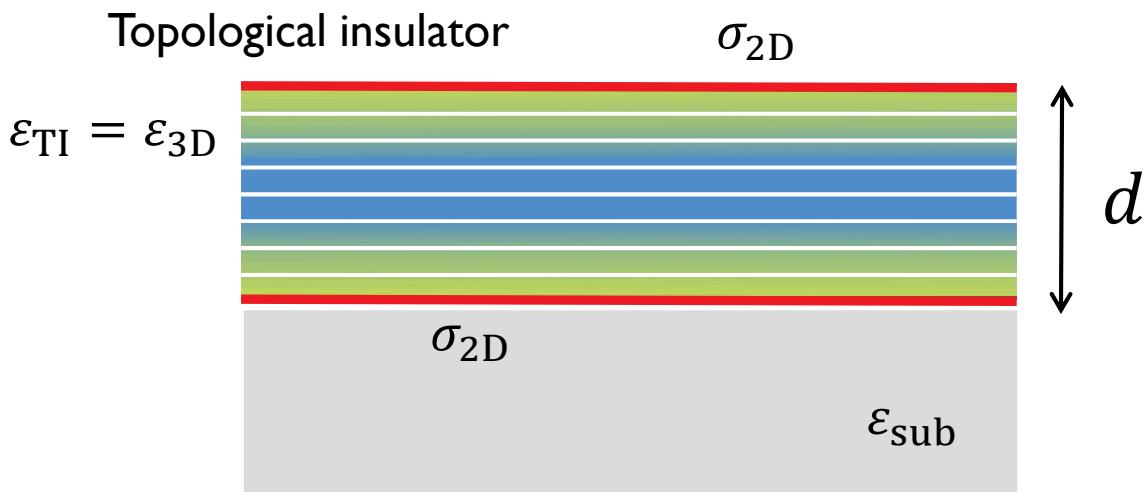
$$q(\omega) = \frac{k_p}{k_0} = i \frac{c}{4\pi} \frac{\varepsilon_{\text{sub}} + 1}{\sigma(\omega)}$$



Analogy from circuit design:
parallel connection of resistors



Polariton wavector is proportional to inversed total sheet conductivity



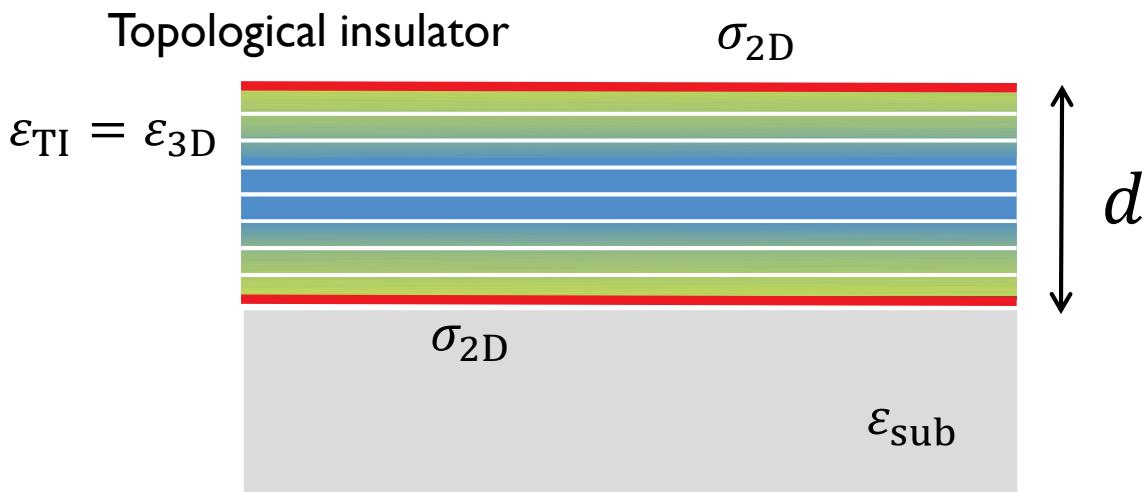
$$\omega_p^2 = \frac{2\alpha_d v_F E_F}{\hbar(\varepsilon_{sub} + 1)} k_p \left[1 + \frac{k_p d \varepsilon_{TI}}{\varepsilon_{sub} + 1} \right]^{-1}$$

Phys. Rev. B 88, 205427 (2013)

$$q(\omega) = \frac{k_p}{k_0} = i \frac{c}{4\pi} \frac{\varepsilon_{sub} + 1}{\sigma(\omega)}$$

$$\sigma(\omega) = 2\sigma_{2D} + \sigma_{3D} = 2(\sigma_{Dirac} + \sigma_{2DEG}) + \sigma_{Drude} + \sigma_{ph}$$

Polariton wavevector is proportional to inversed total sheet conductivity



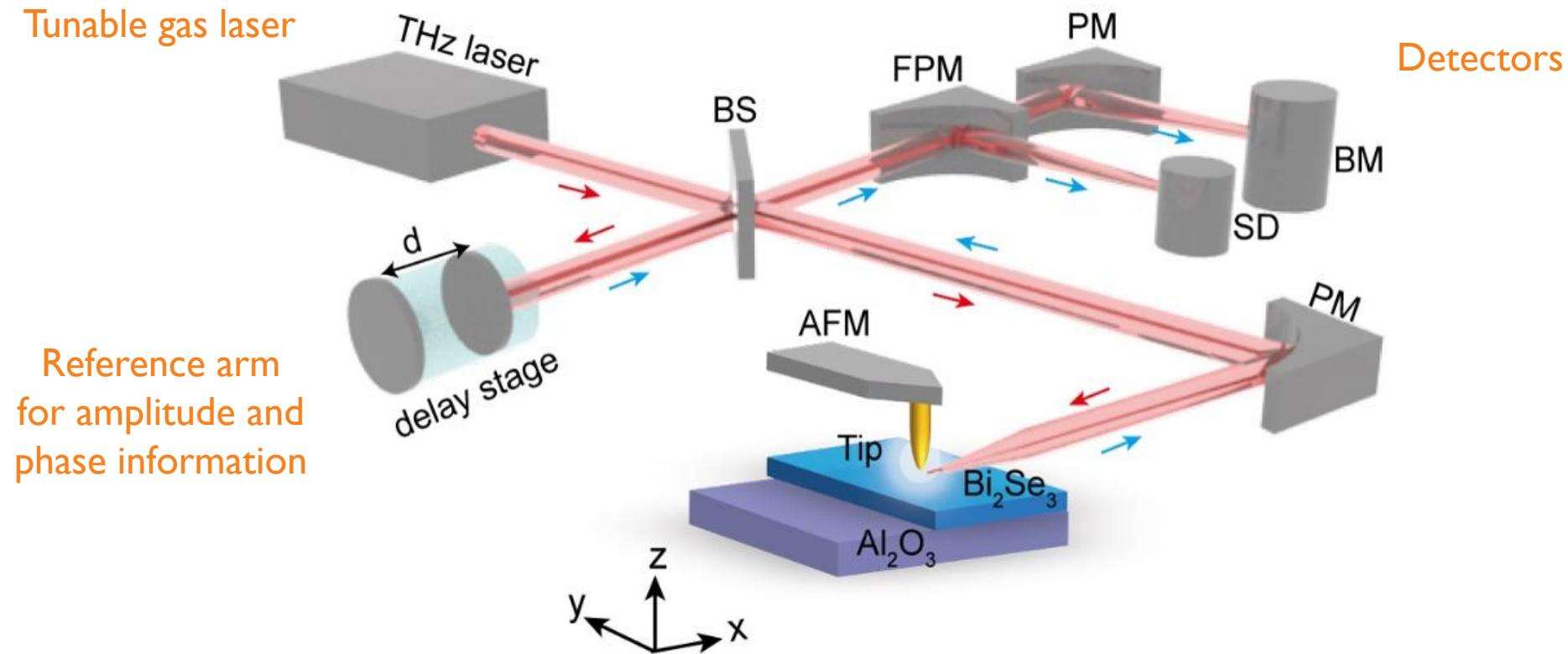
$$\omega_p^2 = \frac{2\alpha_d v_F E_F}{\hbar(\varepsilon_{sub} + 1)} k_p \left[1 + \frac{k_p d \varepsilon_{TI}}{\varepsilon_{sub} + 1} \right]^{-1}$$

Phys. Rev. B 88, 205427 (2013)

$$q(\omega) \propto \frac{1}{\sigma(\omega)}$$

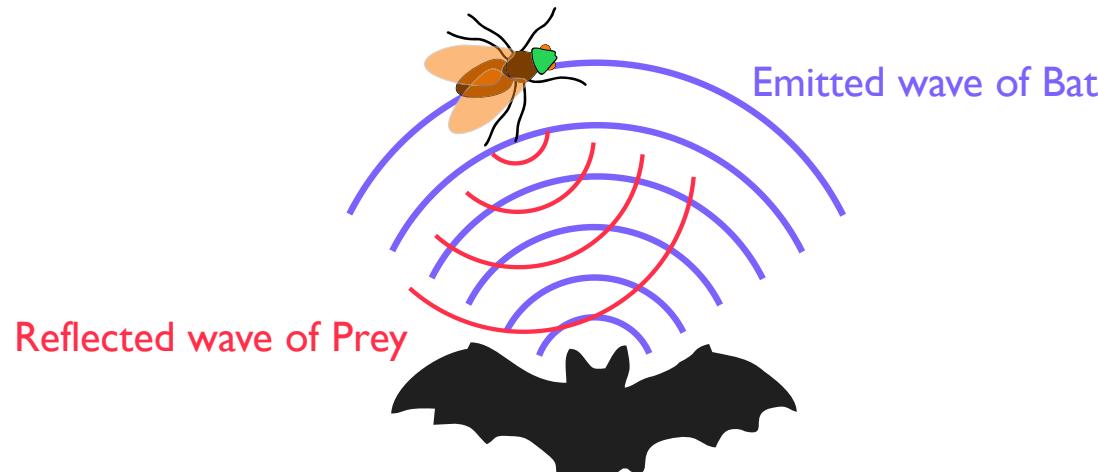
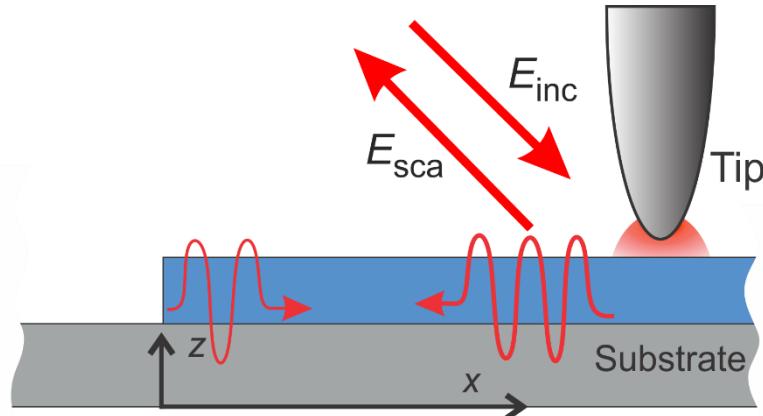
$$\sigma(\omega) = 2\sigma_{2D} + \sigma_{3D} = 2(\sigma_{Dirac} + \sigma_{2DEG}) + \sigma_{Drude} + \sigma_{ph}$$

| THz s-SNOM setup for spectroscopic nanoimaging

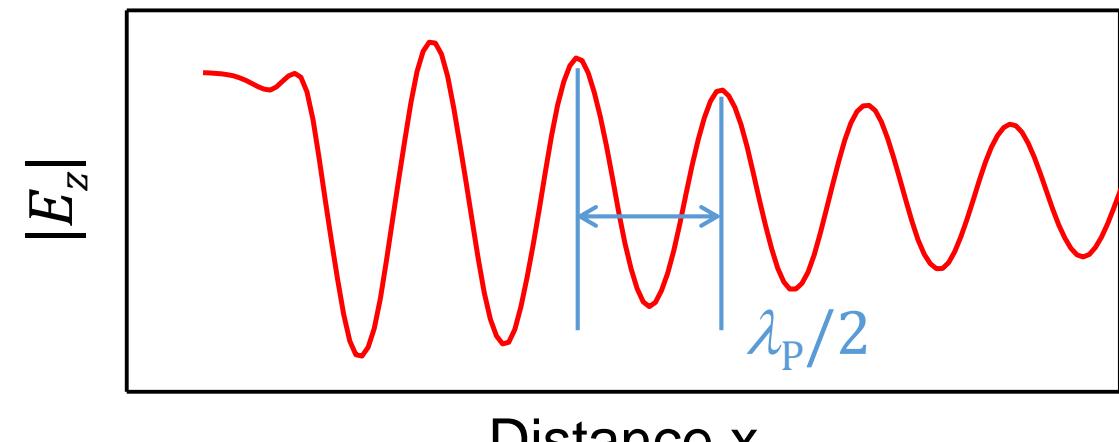
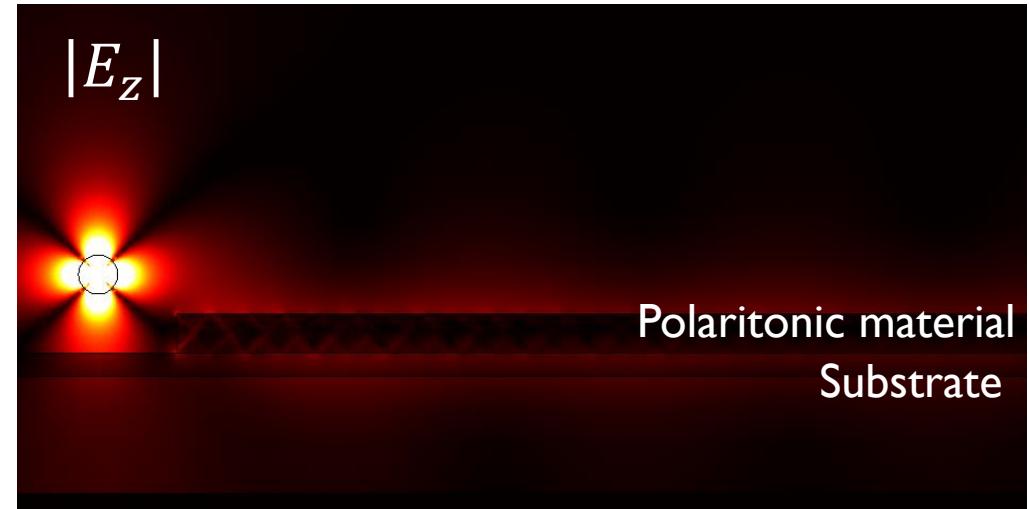


See also ACS Photonics 2020, 7, 12, 3499–3506

Polariton interferometry reveal the complex-valued polariton wavevector

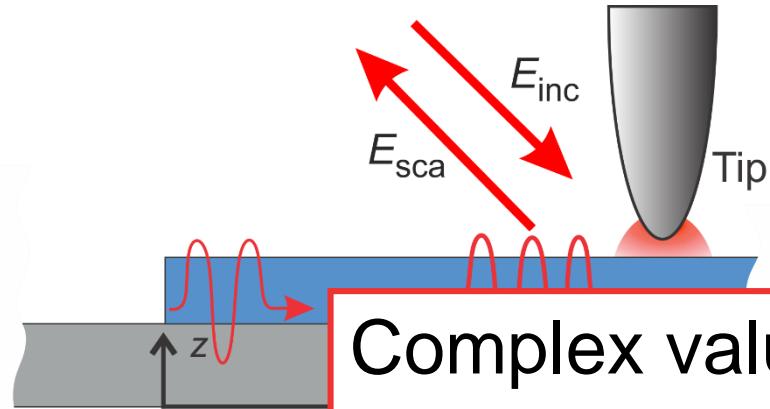


Point dipole is mimicking the SNOM tip

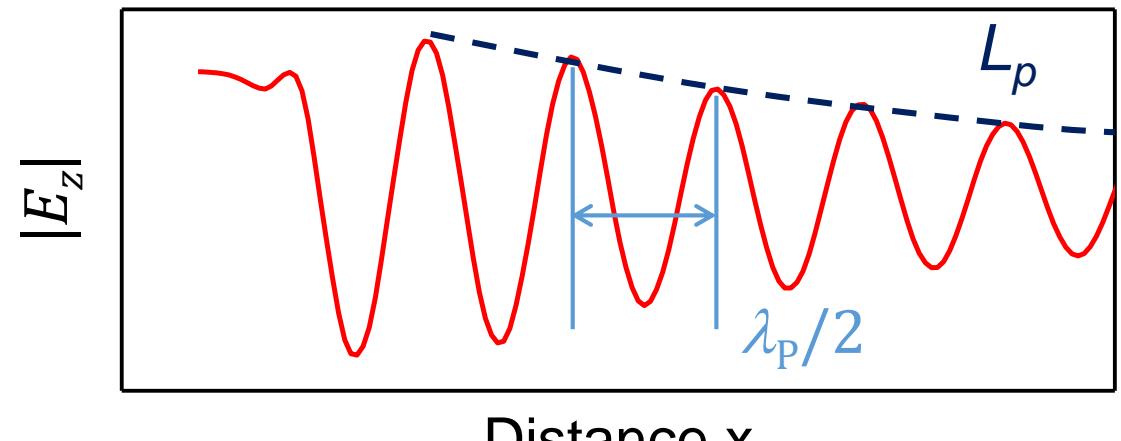
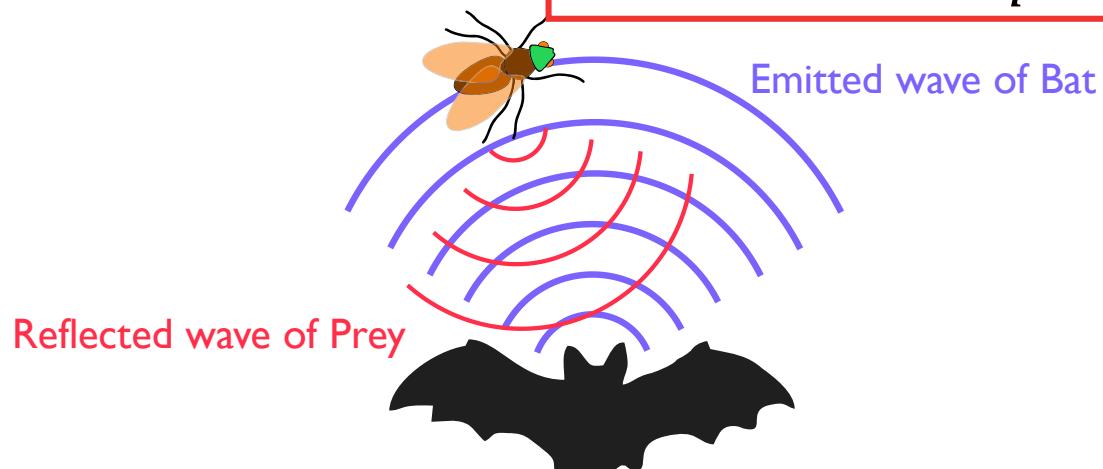


Polariton interferometry reveal the complex-valued polariton wavevector

Point dipole is mimicking the SNOM tip

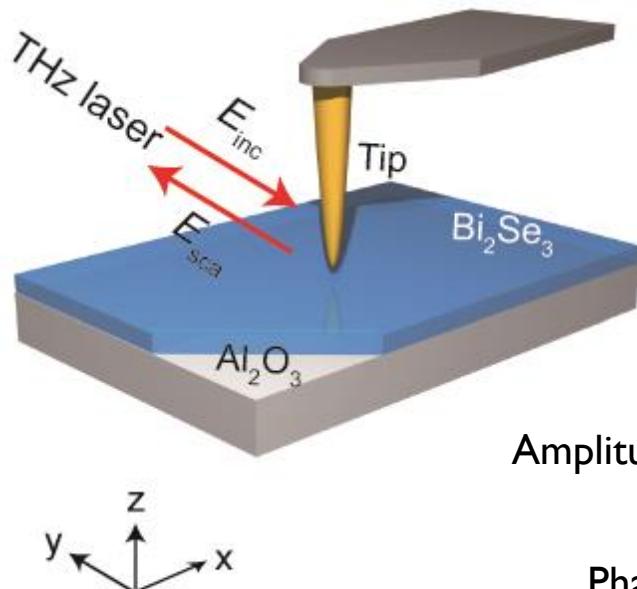


Complex valued polariton wavevector
 $k_p = k'_p + ik''_p$

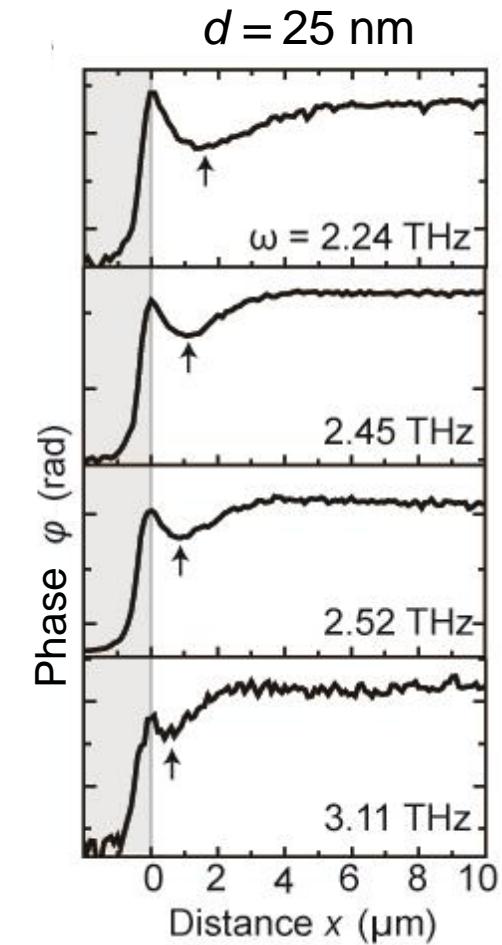
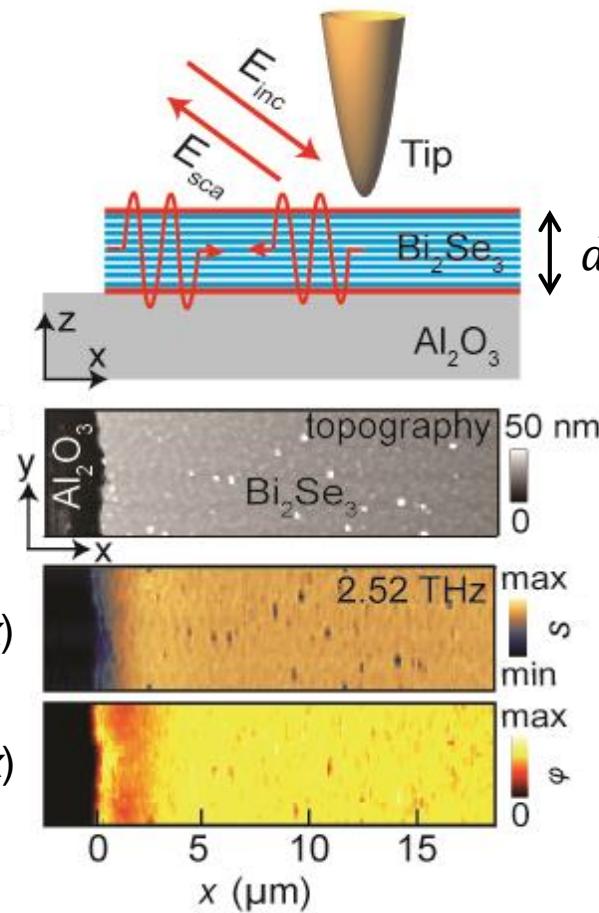


We performed polariton interferometry in Bi_2Se_3

Interferometric detection yields amplitude, $s(x)$, and phase, $\varphi(x)$

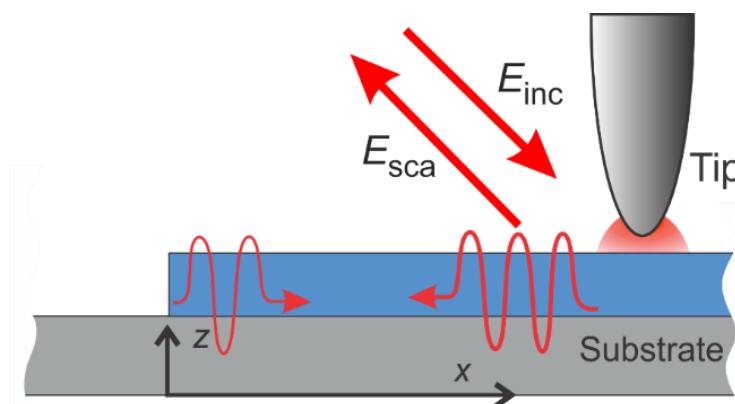


Amplitude, $s(x)$
Phase, $\varphi(x)$



We used complex-valued analysis of THz line profiles to extract polariton wavevector

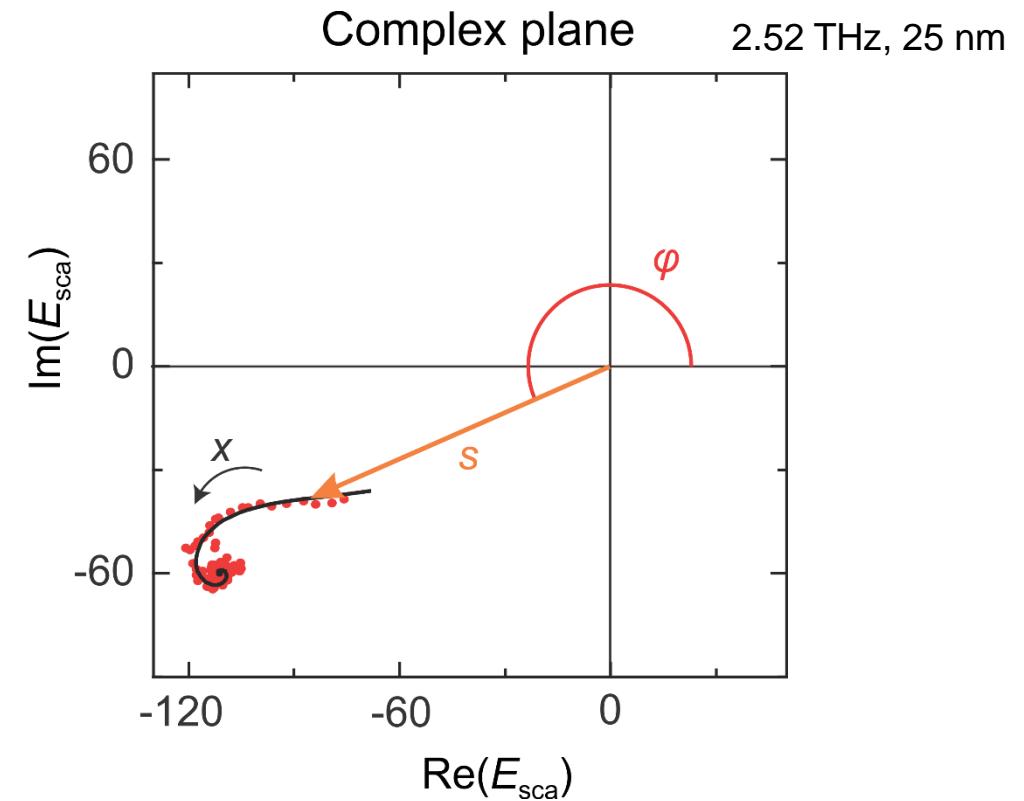
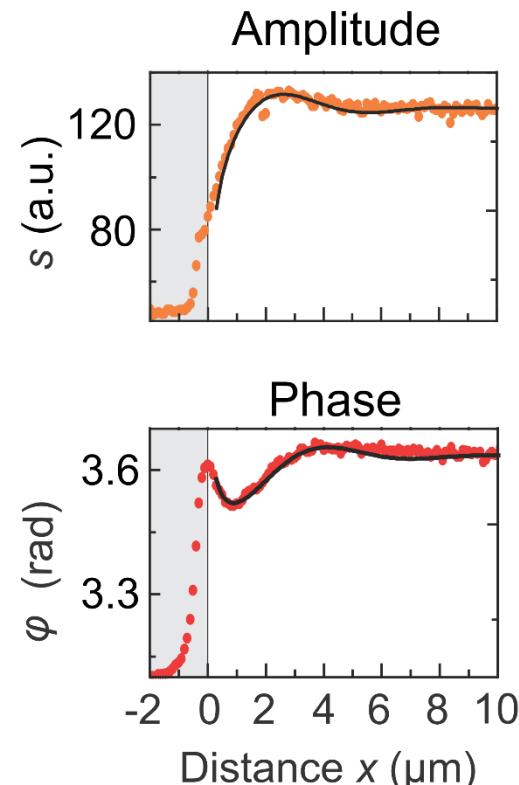
$$E_{\text{sca}}(x) = A \frac{e^{i2k_p x}}{\sqrt{x}} + C$$



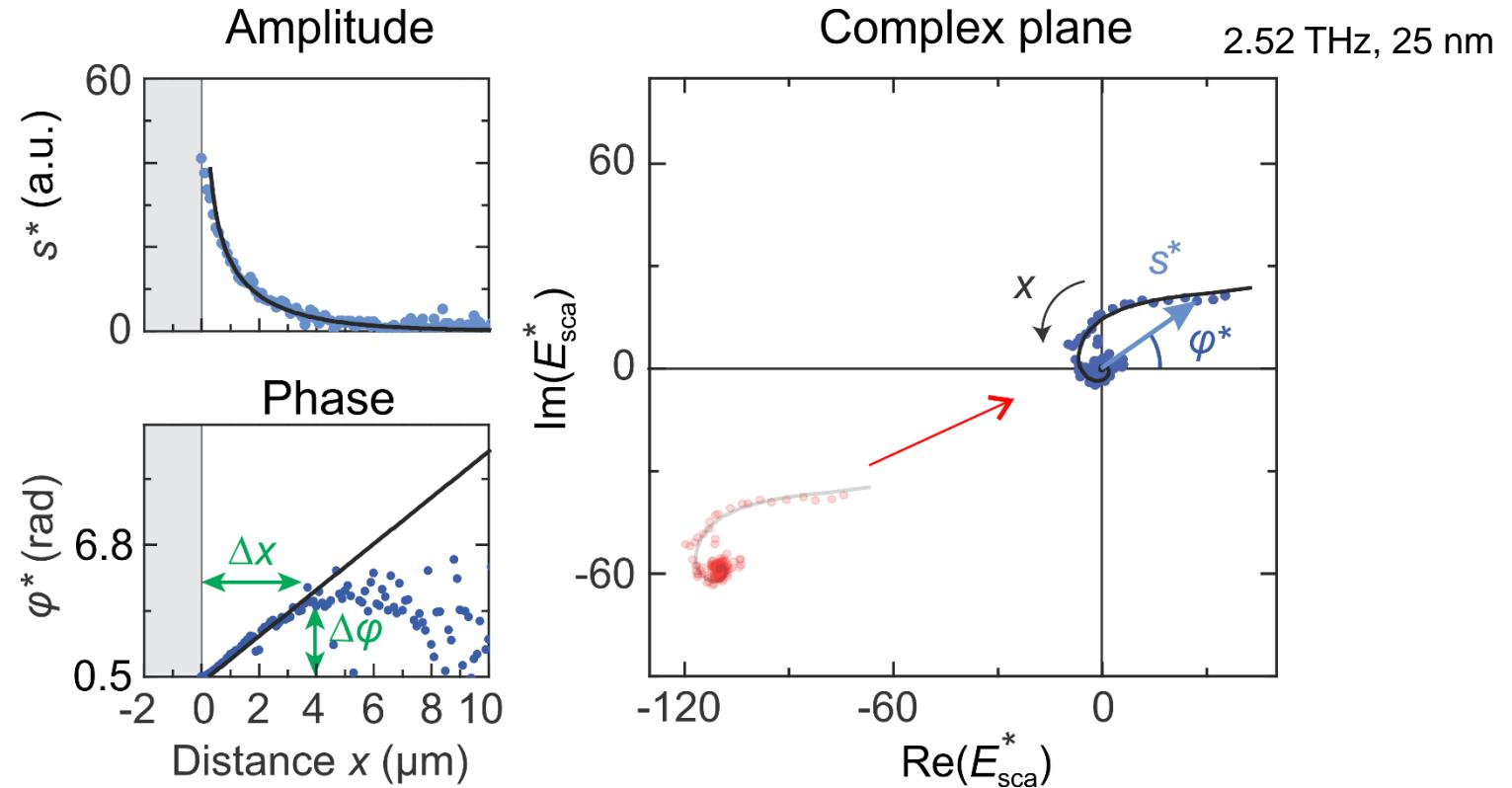
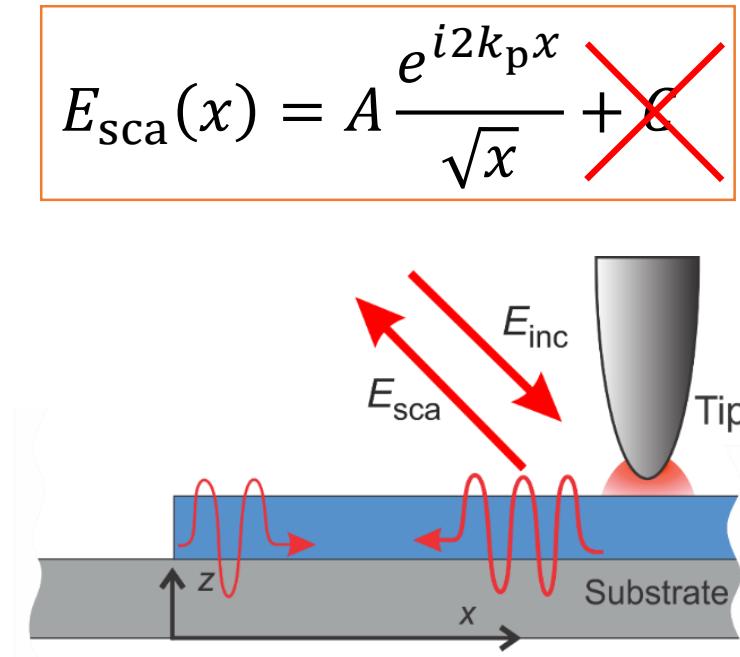
A – complex amplitude

C – complex offset

k_p – complex polariton wavevector

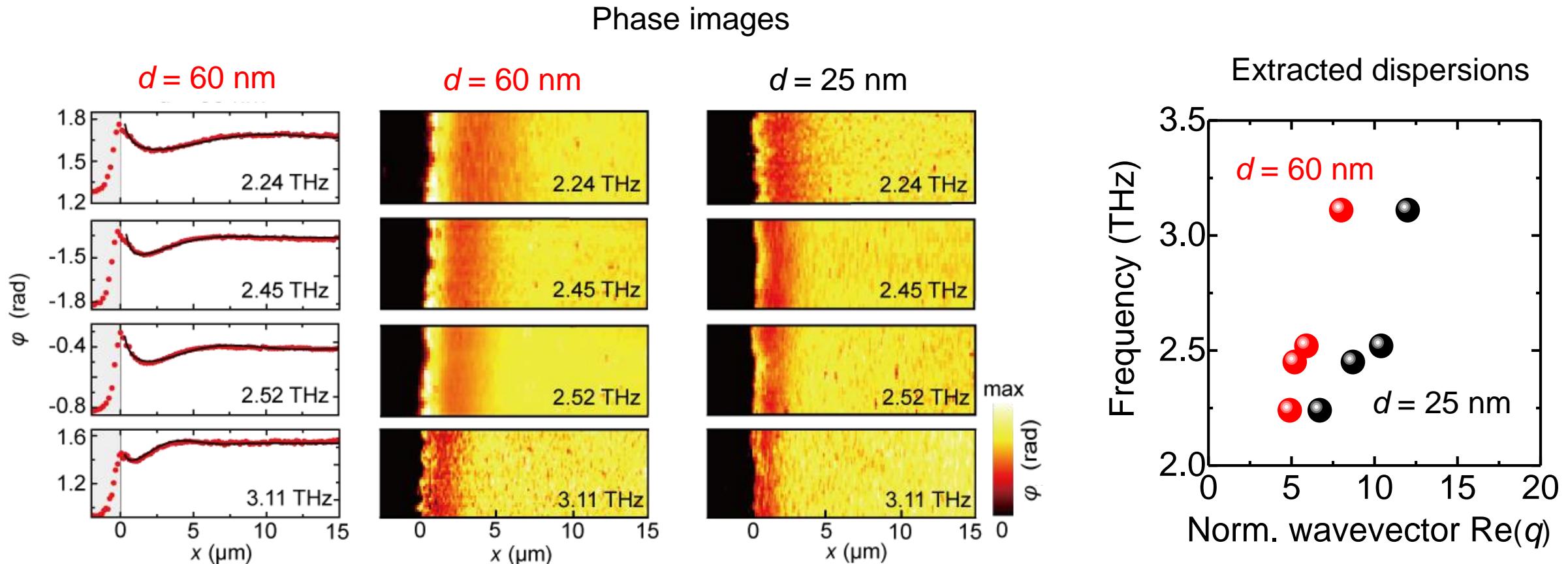


Complex offset subtraction allows to disentangle polariton amplitude and phase



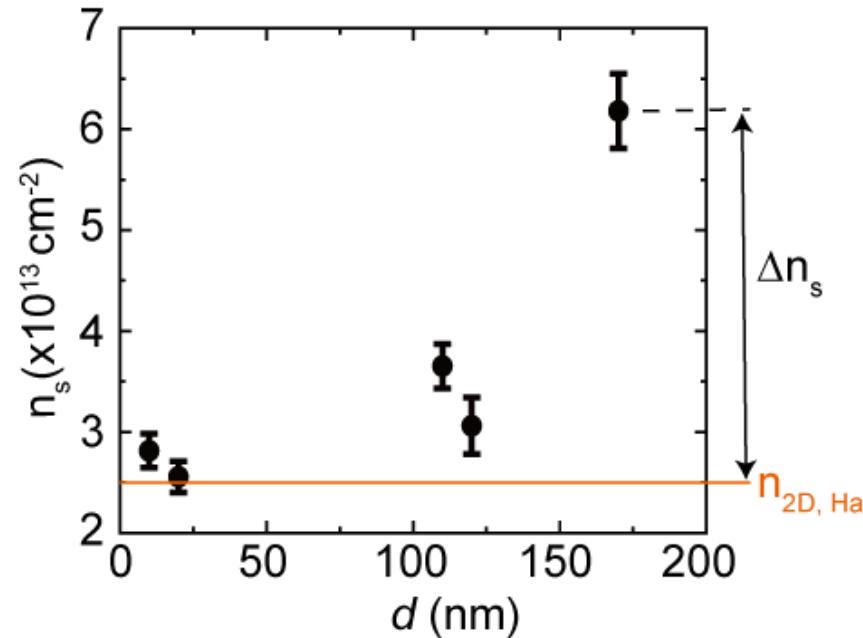
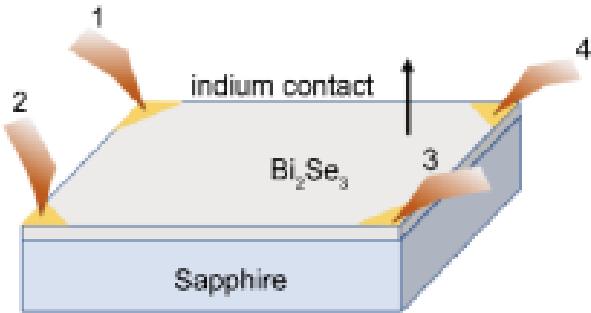
- Polariton wavelength from the linear phase ramp $\lambda_p = 4\pi\Delta x/\Delta\varphi$

Nanoimaging of Bi_2Se_3 at different frequencies



- Complex-valued analysis allows to extract polariton dispersion for 25 and 60 nm flakes

Hall measurements provide an estimation of surface and bulk carrier concentrations



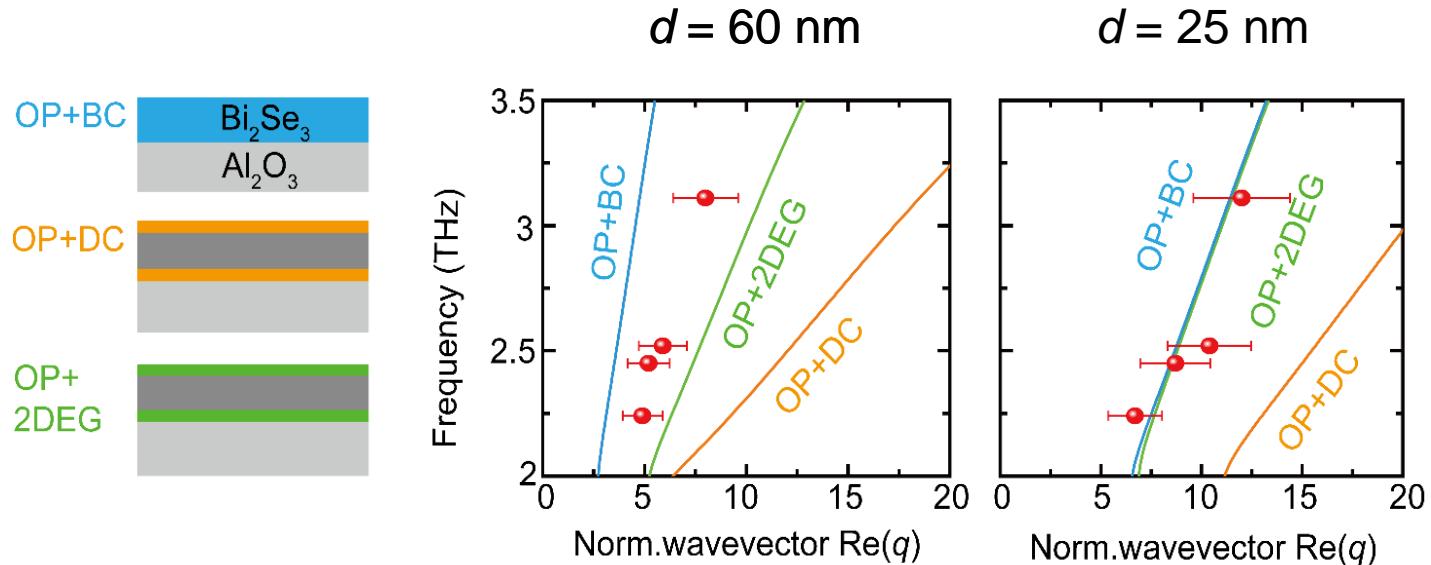
Thickness-dependent sheet carrier concentration from Hall measurements.

- Hall measurements do not allow to measure concentration of different type of carriers

→ $n_{2D} = 2.5 \times 10^{13} \text{ cm}^{-2}$ from very thin film;

→ $n_{3D}^{\text{bulk}} = \frac{\Delta n_s}{170 \text{ nm}} = 2.15 \times 10^{18} \text{ cm}^{-3}$ from 170 nm

Exploring origins of THz polaritons in Bi_2Se_3

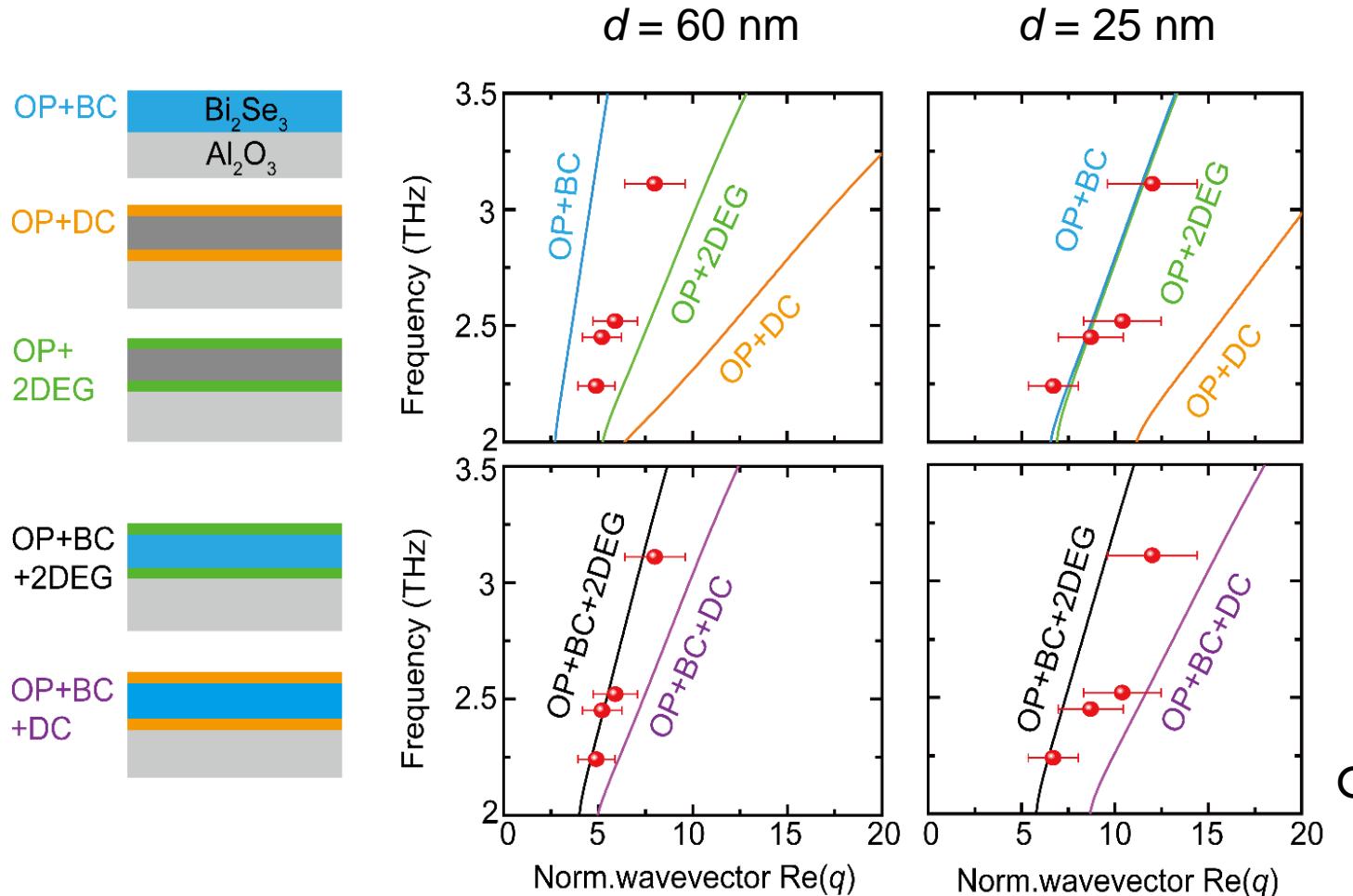


All carrier concentrations from
the Hall measurements

$$\sigma(\omega) = \sigma_{\text{ph}} + \sigma_{\text{Drude}} + \sigma_{\text{2DEG}} + \sigma_{\text{Dirac}}$$

Bulk carriers
Optical phonons + 2DEG
Dirac carriers

Exploring origins of THz polaritons in Bi_2Se_3



All carrier concentrations from
the Hall measurements

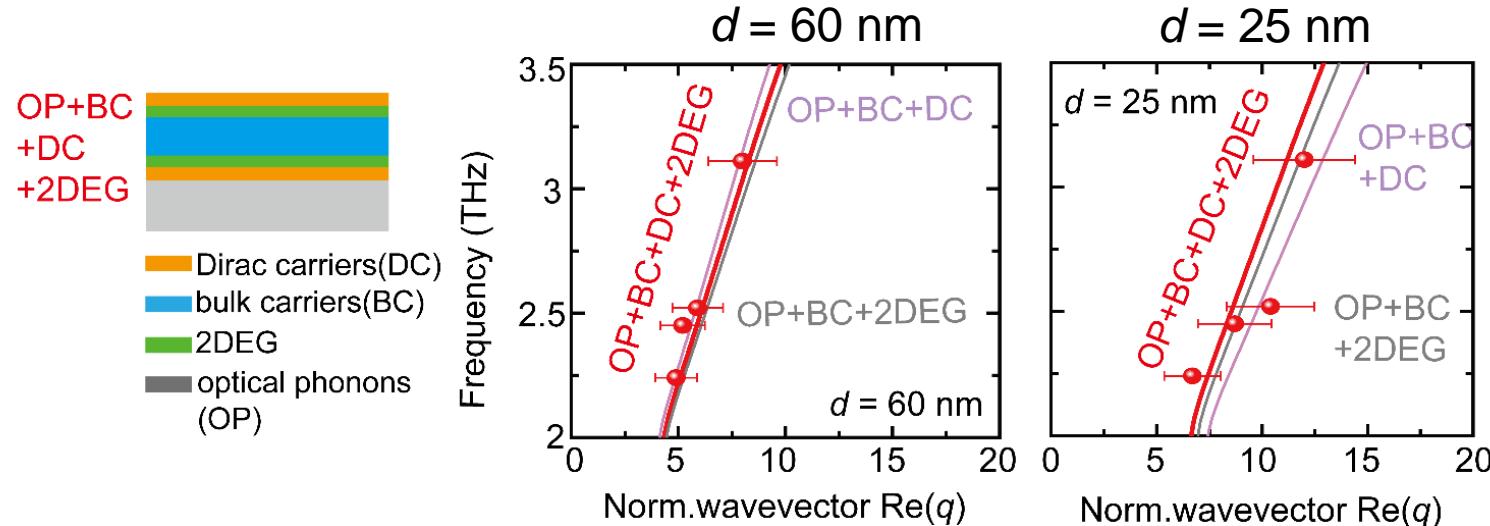
$$\sigma(\omega) = \sigma_{\text{ph}} + \sigma_{\text{Drude}} + \sigma_{2\text{DEG}} + \sigma_{\text{Dirac}}$$

Bulk carriers
Optical phonons + 2DEG
Dirac carriers

$$\sigma(\omega) = \sigma_{\text{ph}} + \sigma_{\text{Drude}} + \sigma_{2\text{DEG}} + \sigma_{\text{Dirac}}$$

Optical phonons + bulk electrons +
2DEG
Dirac carriers

We can fit polariton dispersion in multiple ways



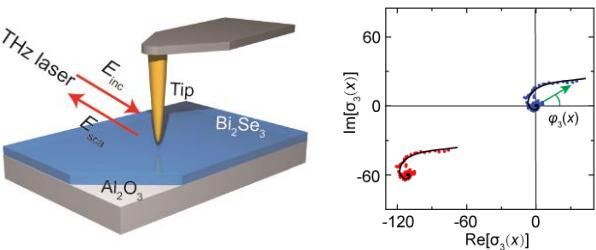
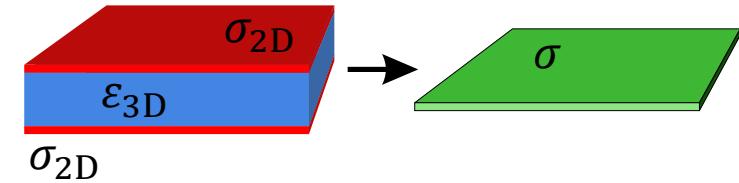
Carrier concentration
as a fit parameter



- Our fitting results indicate the hybrid origin of polaritons in Bi_2Se_3

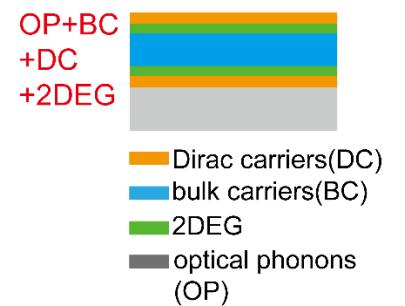
Summary

- Effective conductivity model for the analytical analysis of polariton dispersion in the complex multi layer system



- Complex-valued analysis for the determination of polariton wavevector and propagation length of polaritons in TI

- Polariton dispersion can be explained by simultaneously coupling of THz radiation to different matter excitations



Acknowledgements



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Nano optics group

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Rainer Hillenbrand



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DIPC, Spain

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Alexey Nikitin



University of Delaware, USA

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Greeshma Chandan
Stephanie Law

